Transistors Panasonic

## 2SD1821

### Silicon NPN epitaxial planar type

For high breakdown voltage low-frequency and low-noise amplification

#### ■ Features

- $\bullet$  High collector-emitter voltage (Base open)  $V_{CEO}$
- Low noise voltage NV
- S-Mini type package, allowing downsizing of the equipment and automatic insertion through the tape packing.

#### ■ Absolute Maximum Ratings $T_a = 25$ °C

Parameter	Symbol	Rating	Unit	
Collector-base voltage (Emitter open)	V <sub>CBO</sub>	150	V	
Collector-emitter voltage (Base open)	V <sub>CEO</sub>	150	V	
Emitter-base voltage (Collector open)	V <sub>EBO</sub>	5	V	
Collector current	$I_{\mathrm{C}}$	50	mA	
Peak collector current	$I_{CP}$	100	mA	
Collector power dissipation	P <sub>C</sub>	150	mW	
Junction temperature	Tj	150	°C	
Storage temperature	T <sub>stg</sub>	-55 to +150	°C	

#### ■ Package

- Code
  - SMini3-G1
- Pin Name
  - 1. Base
  - 2. Emitter
  - 3. Collector
- Marking Symbol: P

### ■ Electrical Characteristics $T_a = 25$ °C±3°C

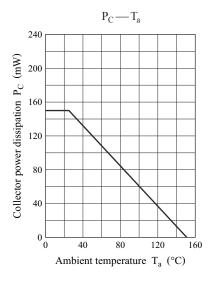
Parameter	Symbol	Conditions	Min	Тур	Max	Unit
Collector-emitter voltage (Base open)	V <sub>CEO</sub>	$I_C = 100 \mu\text{A}, I_B = 0$	150	),		V
Emitter-base voltage (Collector open)	$V_{\mathrm{EBO}}$	$I_E = 10 \mu A, I_C = 0$	5			V
Collector-base cutoff current (Emitter open)	$I_{CBO}$	$V_{CB} = 100 \text{ V}, I_E = 0$	,.7		1	μA
Forward current transfer ratio *	$h_{\mathrm{FE}}$	$V_{CE} = 5 \text{ V}, I_{C} = 10 \text{ mA}$	130		330	_
Collector-emitter saturation voltage	V <sub>CE(sat)</sub>	$I_C = 30 \text{ mA}, I_B = 3 \text{ mA}$			1	V
Transition frequency	$f_T$	$V_{CB} = 10 \text{ V}, I_E = -10 \text{ mA}, f = 200 \text{ MHz}$		150		MHz
Collector output capacitance (Common base, input open circuited)	C <sub>ob</sub>	$V_{CB} = 10 \text{ V}, I_E = 0, f = 1 \text{ MHz}$		2.3		pF
Noise voltage	NV	$V_{CB} = 10 \text{ V}, I_C = 1 \text{ mA}, G_V = 80 \text{ dB},$ $R_g = 100 \text{ k}\Omega, \text{Function} = \text{FLAT}$		150		mV

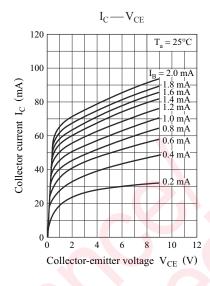
Note) 1. Measuring methods are based on JAPANESE INDUSTRIAL STANDARD JIS C 7030 measuring methods for transistors.

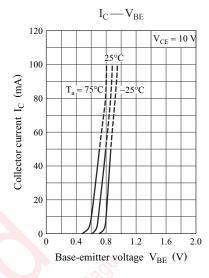
#### 2. \*: Rank classification

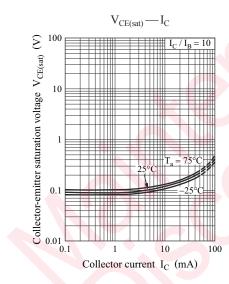
Rank	R	S
$h_{\mathrm{FE}}$	130 to 220	185 to 330

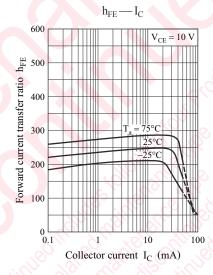
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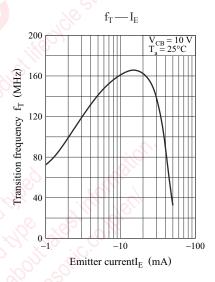


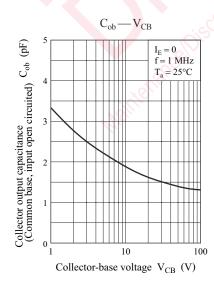








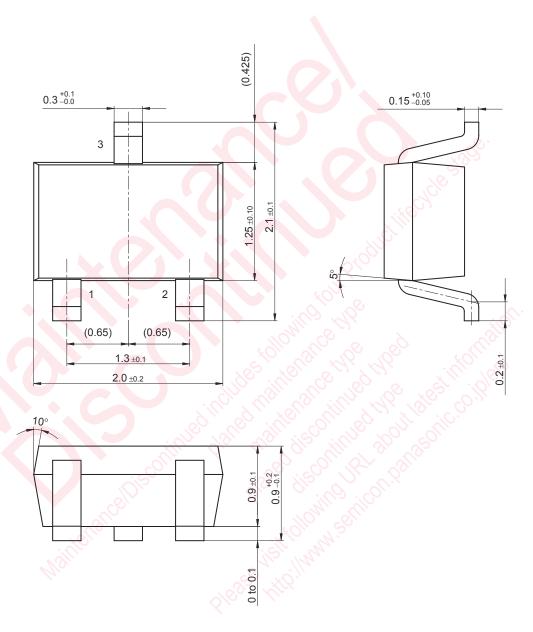




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Panasonic 2SD1821

SMini3-G1 Unit: mm



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